In Re Patent Application of:	
Steven N. Towle	Examiner: McDonald, Rodney Glenn
Application No.: 10/082,997	Art Unit: 1753
Filed: February 25, 2002	RECEIVED
For: METHOD FOR IMPROVING THERMAL ) STABILITY OF FLUORINATED AMORPHOUS	DEC 15 2003
CARBON LOW DIELECTRIC (CONSTANT MATERIALS )	TC 1700
Commissioner for Patents	
P.O. Box 1450	
Alexandria, Virginia 22313-1450	

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If there are any additional charges, please charge Deposit Account No. 02-2660						
Respectfully submitted,						
BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP						
Dated: 12/3, 2003 Heather M. Molleur Reg. No. 50,432	Dated:					

12400 Wilshire Blvd. Seventh Floor Los Angeles, CA 90025 (408) 720-8300 OTP E 10 18 2003 18

Substitute fo			e .c	Compl	lete if Known		
	INFORM	MATION DISCLOSUR	BOY TO A DE WART	Application Number	10/082,997		
STATEMENT BY APPLICANT			T	Filing Date	February 25, 2002	, 2002	
(use as many sheets as necessary)		First Named Inventor:	Steven N. Towle				
				Art Unit	1753		
				Examiner Name	McDonald, Rodney Glenn		
Sheet	1	of 1		Attorney Docket Number	42390P5783D		
		NO	N PATENT LIT	ERATURE DOCUMENTS			
Examiner Initials*	Cite No <sup>1</sup>						
		ENDO, KAZUHIKO, ET AL., Fluorinated amorphous carbon thin films grown by helicon plasma enhanced chemical vapor deposition for low dielectric constant interlayer dielectrics, Appl. Phys. Lett. 68 (20) 13 May 1996, pgs. 2864-2866, © American Institute of Physics.  ENDO, KAZUHIKO, ET AL., Fluorinated amorphous carbon thin films grown by plasma enhanced chemical vapor deposition for low dielectric constant interlayer dielectrics, J. Appl. Phys. 78 (2), 15					
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				ption spectroscopy of boron/carbolls 217 (1994) 154-160, pgs. 154-			

<sup>\*</sup>Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in

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